

Test report No.

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: 32DE0300-HO-02-R1 : 1 of 27

Issued date

: March 14, 2012

Revised date FCC ID

: March 16, 2012 : YS34D454C2D5002

# **RADIO TEST REPORT**

Test Report No.: 32DE0300-HO-02-R1

**Applicant** 

MITSUBISHI ELECTRIC CORPORATION

**Type of Equipment** 

Card Reader

Model No.

: UCR-8213

**Test regulation** 

FCC Part 15 Subpart C: 2012

FCC ID

YS34D454C2D5002

**Test Result** 

Complied

- 1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
- 2. The results in this report apply only to the sample tested.
- 3. This sample tested is in compliance with above regulation.

:

- 4. The test results in this report are traceable to the national or international standards.
- 5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.
- 6. This report is a revised version of 32DE0300-HO-02. 32DE0300-HO-02 is replaced with this report.

Date of test:

March 1 to 9, 2012

Representative test engineer:

Hiroshi Kukita Engineer of WiSE Japan, UL Verification Service

Approved by:

Masanori Nishiyama Leader of WiSE Japan, UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. \*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap

UL Japan, Inc.

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## **SECTION 1: Customer information**

Company Name : MITSUBISHI ELECTRIC CORPORATION

Address : No.1, Hishi-machi, Inazawa-shi, Aichi-ken, 492-8682, Japan

Telephone Number : +81-587-24-5560 Facsimile Number : +81-587-24-5768 Contact Person : Koki Okunishi

## **SECTION 2:** Equipment under test (E.U.T.)

#### 2.1 Identification of E.U.T.

Type of Equipment : Card Reader Model No. : UCR-8213

Serial No. : Refer to Section 4, Clause 4.2

Rating : DC 24V

Receipt Date of Sample : February 27, 2012

Country of Mass-production : Japan

Condition of EUT : Production model

Modification of EUT : No Modification by the test lab

#### 2.2 Product Description

Model No: UCR-8213, referred to as the EUT in this report, is the Card Reader. This model is Keypad Type.

EUT has a series model.

UCR-8203: Plain Type : Only cover is changed. Printed circuit boards are same.

\* There is no difference in radio specification.

**General Specification** 

Clock frequency(ies) in the system : 31.3344MHz (Oscillator), 27.12MHz (Cristal)

**Radio Specification** 

Radio Type : Transceiver
Frequency of Operation : 13.56MHz
Power Supply (inner) : DC 3.3V, DC 7V
Antenna type : Pattern antenna (Coil)
Operating Temperature : -10deg.C. to +40deg.C.

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# **SECTION 3: Test specification, procedures & results**

#### 3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2012, final revised on February 1, 2012

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators

Section 15.207 Conducted limits

Section 15.225: Operation within the band 13.110-14.010MHz

#### 3.2 Procedures and results

Item	Test Procedure	Specification	Worst margin	Results	Remarks
Conducted emission	ANSI C63.4:2003 7. AC powerline conducted emission measurements	Section 15.207	[QP]10.4dB (27.12000MHz, L, with Card) [AV]0.3dB (27.12000MHz,	Complied	-
	<ic>RSS-Gen 7.2.2</ic>	<ic>RSS-Gen 7.2.2</ic>	L, with Card)		
Electric Field Strength of Fundamental Emission	ANSI C63.4:2003 13. Measurement of intentional radiators <ic> RSS-Gen 4.8, 4.11</ic>	Section 15.225(a) <ic>RSS-210 A2.6</ic>	50.0dB 13.56000MHz, QP, 0deg., with Card	Complied	Radiated
Spectrum Mask	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.9, 4.11</ic>	Section 15.225(b)(c) <ic> RSS-210 A2.6</ic>	30.7dB 13.55300MHz, QP, 0deg., with Card	Complied	Radiated
20dB Bandwidth	ANSI C63.4:2003 13. Measurement of intentional radiators <ic> -</ic>	Section15.215(c)	See data	Complied	Radiated
Electric Field Strength of Spurious Emission	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.9, 4.11</ic>	Section15.209, Section 15.225 (d) <ic>RSS-210 A2.6</ic>	0.7dB 325.250MHz, Horizontal, QP, with Card	Complied	Radiated
Frequency Tolerance	ANSI C63.4:2003 13. Measurement of intentional radiators <ic>RSS-Gen 4.7</ic>	Section15.225(e) <ic> RSS-210 A2.6</ic>	See data	Complied	Radiated
Note: UL Japan, Inc.'s l	EMI Work Procedures No.	13-EM-W0420 and 13	-EM-W0422		

# FCC 15.31 (e)

This EUT provides stable voltage (DC 3.3V, DC 7V) constantly to EUT (RF part) regardless of input voltage. Therefore, this EUT complies with the requirement.

#### FCC Part 15.203 Antenna requirement

The antenna is not removable from the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

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#### 3.3 Addition to standard

No.	Item	<b>Test Procedure</b>	Specification	Remarks	Deviation	Worst margin	Results
1	99% Occupied	RSS-Gen 4.6.1	RSS-Gen 4.6.1	Radiated	N/A	N/A	N/A
	Band Width						

Other than above, no addition, exclusion nor deviation has been made from the standard.

### 3.4 Uncertainty

#### **EMI**

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission
(semi-	( <u>+</u> dB)
anechoic	150kHz-30MHz
chamber)	
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room (semi- anechoic chamber)	Radiated emission (10m*)( <u>+</u> dB)				
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz		
No.1	4.1dB	5.0dB	4.8dB		
No.2	-	-	1		
No.3	-	-	-		
No.4	-	-	_		

<sup>\*10</sup>m = Measurement distance

Test room	Radiated emission						
(semi-		(3m*)( <u>+</u> dB)				)( <u>+</u> dB)	$(0.5\text{m*})(\underline{+}\text{dB})$
anechoic	9kHz	30MHz	300MHz	1GHz	10GHz	18GHz	26.5GHz
chamber)	-30MHz	-300MHz	-1GHz	-10GHz	-18GHz	-26.5GHz	-40GHz
No.1	4.2dB	5.0dB	5.1dB	4.7dB	5.7dB	4.4dB	4.3dB
No.2	4.1dB	5.2dB	5.1dB	4.8dB	5.6dB	4.3dB	4.2dB
No.3	4.5dB	5.0dB	5.2dB	4.8dB	5.6dB	4.5dB	4.2dB
No.4	4.7dB	5.2dB	5.2dB	4.8dB	5.6dB	5.1dB	4.2dB

<sup>\*3</sup>m/1m/0.5m = Measurement distance

Frequency counter ( <u>+</u> )				
Normal condition	Extreme condition			
7 x 10 <sup>-6</sup>	9 x 10 <sup>-6</sup>			

## Conducted emission test

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

#### Radiated emission test (3m)

The data listed in this report meets the limits unless the uncertainty is taken into consideration.

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#### 3.5 Test Location

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	FCC	IC Registration	Width x Depth x	Size of	Other
	Registration	Number	Height (m)	reference ground plane (m) /	rooms
	Number			horizontal conducting plane	
No.1 semi-anechoic	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power
chamber					source room
No.2 semi-anechoic	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
chamber	055105	27736 2	7.5 X 5.6 X 5.2III	4.0 X 4.0III	
No.3 semi-anechoic	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3
chamber	146736	2913C-3	12.0 X 6.3 X 3.9111	0.8 x 3.73III	
chamber					Preparation
N. O. I. II. I			40 60 25	27/4	room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4
chamber					Preparation
					room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic	-	-	6.0 x 6.0 x 3.9m	60.60	-
chamber			0.0 x 0.0 x 3.9m	6.0 x 6.0m	
No.6 shielded	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
room					
No.6 measurement	_	_	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	_
room					
No.7 shielded room	_	_	4.7 x 7.5 x 2.7m	4.7 x 7.5m	_
No.8 measurement	-	-	3.1 x 5.0 x 2.7m	N/A	-
room					
No.9 measurement	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
room					
No.10 measurement	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
room					
No.11 measurement	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-
room					
				1	

<sup>\*</sup> Size of vertical conducting plane (for Conducted Emission test): 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

### 3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX.

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# **SECTION 4: Operation of E.U.T. during testing**

#### 4.1 Operating Modes

The mode is used: 1. Transmitting (Tx and Rx) with Card mode

2. Transmitting (Tx and Rx) without Card mode

3. Transmitting (Tx and Rx) without Card (Antenna terminated with dummy load) mode

Justification: The system was configured in typical fashion (as a customer would normally use it) for testing.

Frequency Tolerance:

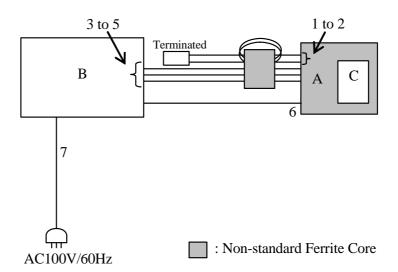
Temperature : -10deg.C to +40deg.C Step 10deg.C

Voltage : Normal Voltage DC 24.0V

Maximum Voltage DC 27.6V, Minimum Voltage DC 20.4V (DC 24.0V ±15%)

\*This EUT provides stable voltage (DC 3.3V, DC 7V) constantly to RF Part regardless of input voltage

#### 4.2 Configuration and peripherals



<sup>\*</sup> Cabling and setup were taken into consideration and test data was taken under worse case conditions.

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**Description of EUT and support equipment** 

No.	Item	Model number	Serial number	Manufacturer	Remark
Α	Card Reader	UCR-8213	1 *1)	MITSUBISHI ELECTRIC	EUT
			2 *2)	CORPORATION	
В	Power supply	PBA15F-24	1522194HR	COSEL	-
С	Card (Type A)	-	-	-	-

#### List of cables used

1	List of Cabits used						
No.	Name	Length (m)	Sh	ield	Remark		
			Cable	Connector			
1	Signal Cable	0.5	Unshielded	Unshielded	Terminated, *a)		
2	Signal Cable	0.5	Unshielded	Unshielded	*a)		
3	DC Power Cable (+)	0.5	Unshielded	Unshielded	*a)		
4	DC Power Cable (-)	0.5	Unshielded	Unshielded	*a)		
5	DC Power Cable (FG)	0.5	Unshielded	Unshielded	*a)		
6	Signal Cable	0.5	Unshielded	Unshielded	-		
7	AC Cable	1.2	Unshielded	Unshielded	-		

#### <Notes for Ferrite cores>

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<sup>\*</sup>a) 1 Ferrite Core, Model No. SFT59SH (Manufacturer: TKK), 2cm from Item A, 3 turns.

<sup>\*</sup>This is Removal Ferrite Core that is included in finished goods.

<sup>\*1)</sup> Used for all tests except for 13.56MHz of Conducted emission test with Card (Antenna was terminated by 50 ohms)

<sup>\*2)</sup> Used for 13.56MHz of Conducted emission test with Card (Antenna was terminated by 50 ohms)

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# **SECTION 5: Conducted emission**

#### 5.1 Operating environment

Test place : No.2 semi anechoic chamber

Temperature : See data Humidity : See data

#### 5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/ an AMN to the input power source. All unused 50ohm connectors of the LISN/ AMN were resistively terminated in 50ohm when not connected to the measuring equipment.

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT on a horizontal conducting plane 4.0 x 4.0m and a vertical conducting plane 2.0 x 2.0m in a semi Anechoic Chamber. Photographs of the set up are shown in Appendix 3.

#### 5.3 Test conditions

Frequency range : 0.15MHz-30MHz

EUT position : Table top EUT operation mode : See Clause 4.1

#### 5.4 Test procedure

The AC Mains Terminal Continuous disturbance Voltage had been measured with the EUT in the semi Anechoic Chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains Network (AMN). An overview sweep with peak detection has been performed.

The measurements had been performed with a quasi-peak detector and if required, with an average detector. The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : QP and AV
IF Bandwidth : 9kHz

5.5 Test result

Summary of the test results: Pass

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# SECTION 6: Radiated emission (Fundamental, Spurious Emission and Spectrum Mask)

#### Test Procedure

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical (angle of loop antenna: 0deg., 45deg., 90deg., and 135 deg.) and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

#### Test Antennas are used as below;

Frequency	Below 30MHz	30MHz to 300MHz	300MHz to 1GHz
Antenna Type	Loop	Biconical	Logperiodic

Frequency	From 9kHz to 90kHz and From 110kHz to 150kHz	From 90kHz to 110kHz	From 150kHz to 490kHz	From 490kHz to 30MHz	From 30MHz to 1GHz
Instrument used			Test Receiver		
Detector	PK/AV	QP	PK/AV	QP	QP
IF Bandwidth	200Hz	200Hz	9kHz	9kHz	120kHz

The worst distance in use between EUT and card was confirmed and the test was performed by following condition.

Below 30MHz: 4cm Above 30MHz: 0cm

\* FCC Part 15 Section 15.31 (f)(2) / IC RSS-Gen 4.11 (9kHz-30MHz)

9kHz - 490kHz [Limit at 3m] = [Limit at 300m] -  $40 \log \left( \frac{3}{300} \right)$ 

490kHz - 30MHz[Limit at 3m] = [Limit at 30m] -  $40\log\left(\frac{3}{30}\right)$ 

Measurement range : 0.09M-1GHz Test data : APPENDIX

Test result : Pass

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<sup>\*</sup>The test was made on EUT in the normal use position.

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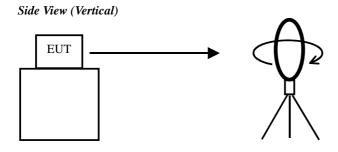
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# **SECTION 7: Other test**

Test	Span	RBW	VBW	Sweep	Detector	Trace	Instrument used
20dB Bandwidth	100kHz	1kHz	3kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak *1)	Max Hold *1)	Spectrum Analyzer
Frequency Tolerance	-	1	1	1	1	-	Frequency counter
*1) The measurem	ent was performed with Peal	detector. Ma	x Hold since the	e duty cycle was not	100%		

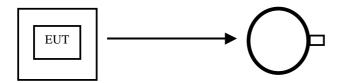
Test data : APPENDIX
Test result : Pass

Figure 1: Direction of the Loop Antenna



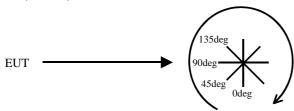
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Top View (Horizontal)



Antenna was not rotated.

#### Top View (Vertical)



Front side: 0 deg.

Forward direction: clockwise

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# **APPENDIX 1: Data of EMI test**

# **Conducted emission**

# DATA OF CONDUCTED EMISSION TEST

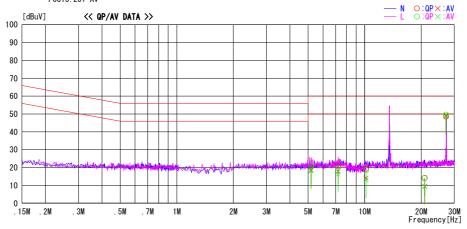
UL Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date : 2012/03/02

Report No. : 32DE0300-H0-02

Temp./Humi. : 21deg. C / 32% RH
Engineer : Hiroshi Kukita

Mode / Remarks : Transmitting (Tx and Rx) with Card mode, Type A

LIMIT : FCC15. 207 QP



Frequency	Reading		Corr.	Resu		Lin			gin		
Frequency	QP	AV	Factor	QP	AV	QP	AV	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
5. 18271	6.8	4. 1	13. 9		18. 0	60.0	50.0	39. 3	32. 0	L	
5. 18422	6. 7	4. 6	13. 9	20.6	18. 5	60.0	50.0	39. 4		N	
7. 21610	5. 7	2. 1	14. 1	19.8	16. 2	60.0	50.0	40. 2	33. 8	L	
7. 21820	6. 5	3. 6	14. 1	20.6	17. 7	60.0	50.0	39. 4	32. 3	N	
10. 17080	4. 1	-1.4	14. 4	18.5	13.0	60.0	50.0	41.5		L	
10. 17120	4. 9	-0.3	14. 4	19.3	14. 1	60.0	50.0	40. 7	35. 9	N	
20. 80240	-1.1	-5. 7	15. 2	14. 1	9. 5	60.0	50.0	45. 9	40. 5	L	
20. 90640	-1.0	-5. 7	15. 2	14. 2	9. 5	60.0	50.0	45. 8	40. 5	N	
27. 12000	33. 0	33. 3	15. 5	48. 5	48. 8	60.0	50.0	11.5		N	
27. 12000	34. 1	34. 2	15. 5	49.6	49. 7	60.0	50.0	10.4	0.3	L	
l											
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\*The test result is rounded off to one or two decimal places, so some differences might be observed.

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# **Conducted emission**

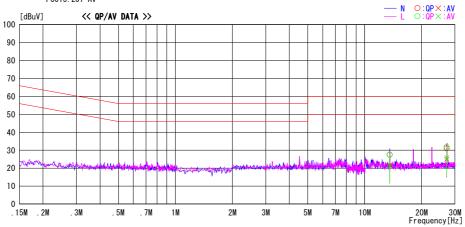
# DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.3 Semi Anechoic Chamber Date: 2012/03/09

Report No. : 32DE0300-H0-02 Temp./Humi. Engineer : 23deg. C / 34% RH : Takeshi Choda

Mode / Remarks : Transmitting (Tx and Rx) without Card (Antenna terminated with dummy load) mode

LIMIT : FCC15. 207 QP FCC15. 207 AV



Frequency	Reading	Level	Corr.	Resu	ılts	Lin	nit	Mar	gin		
	QP	AV	Factor	QP	AV	QP	AV	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
13. 56008	13. 2	7.4	14. 3	27. 5	21. 7	60.0	50. 0	32.5			
27. 12000		10.3	14. 7	31.0			50.0				
13.56008	13. 2	7. 1	14. 3	27. 5			50.0	32.5		L	
27. 12016	17. 1	11.2	14.7	31.8	25. 9	60.0	50. 0	28. 2	24. 1	L	
				İ							
			-	-							

\*The test result is rounded off to one or two decimal places, so some differences might be observed.

# UL Japan, Inc.

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# **Conducted emission**

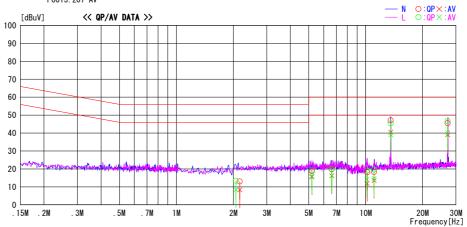
# DATA OF CONDUCTED EMISSION TEST

Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date : 2012/03/02

Report No. : 32DE0300-H0-02 Temp./Humi. Engineer : 21deg. C / 32% RH : Hiroshi Kukita

Mode / Remarks : Transmitting (Tx and Rx) without Card mode, Type A

FCC15. 207 QP FCC15. 207 AV



F	Reading	Level	Corr.	Resu	ılts	Lin	nit	Mar	gin		
Frequency	QP	AV	Factor	QP	AV	QP	AV	QP	AV	Phase	Comment
[MHz]	[dBuV]	[dBuV]	[dB]	[dBuV]	[dBuV]	[dBuV]	[dBuV]	[dB]	[dB]		
2. 16160	-0.4	-5. 1	13. 4	13. 0	8. 3	56.0	46. 0	43.0	37.7	N	
5. 19664	4. 9	1.7	13. 9	18. 8	15. 6	60.0	50.0	41.2	34. 4	N	
6. 62002	5. 8	2. 2	14. 0	19. 8	16. 2	60.0	50.0	40. 2	33.8	N	
10. 18720		-2. 5	14. 4	18. 1	11.9	60.0	50.0	41.9		N	
11.06760	3.8	-0.9	14. 5	18. 3	13.6	60.0	50.0	41.7		N	
13. 56000		25. 7	14. 8	47. 1	40. 5	60.0	50.0				
27. 12000	30. 0	23.6	15. 5	45. 5	39. 1	60.0	50.0	14. 5		N	
2.06360	0.0	-5.0	13. 4	13. 4	8. 4	56.0	46. 0	42.6	37. 6	L	
5. 19598	5. 3	2. 0	13. 9	19. 2	15. 9	60.0	50.0	40.8	34. 1	L	
6. 61856	6. 0	2. 2	14. 0	20. 0	16. 2	60.0	50.0	40.0		L	
10. 14352		-0.1	14. 4	19. 0	14. 3	60.0	50.0	41.0		L	
11.06460		0. 2	14. 5	19. 6	14. 7	60.0	50.0	40.4	35. 3	L	
13. 56000		24. 3	14.8		39. 1	60.0	50.0	14. 6		L	
27. 12000	31. 2	24. 8	15. 5	46. 7	40. 3	60.0	50.0	13. 3	9. 7	L	

\*The test result is rounded off to one or two decimal places, so some differences might be observed.

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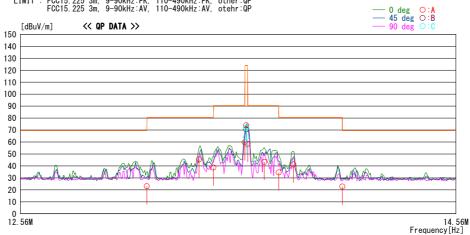
# **Fundamental emission and Spectrum Mask**

# DATA OF RADIATED EMISSION TEST UL Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date: 2012/03/01

Report No. : 32DE0300-H0-02 Temp./ Humi. Engineer : 21deg. C / 32% RH : Hiroshi Kukita

Mode / Remarks : Transmitting (Tx and Rx) with Card mode (Card distance: 4cm)

FCC15.225 3m, 9-90kHz:PK, 110-490kHz:PK, other:QPFCC15.225 3m, 9-90kHz:AV, 110-490kHz:AV, otehr:QP



Freq.	Reading	DET	Ant. Fac	Loss	Gain	Result	Limit	Margin	Antenna		Table	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	[deg]		[deg]	
13. 11000	29. 2	QP	19. 1	6. 9	32. 2	23.0	69.5		0	Α	359	
13. 34521	51.7	QP	19. 0	6. 9	32. 2	45.4	80.5	35. 1	0	Α	359	
13. 41000	45.0		19. 0	6. 9	32. 2	38.7	80.5	41.8	0	Α	359	
13. 55300	66.0	QP	18. 9	7. 0	32. 2	59.7	90.4	30. 7	0	Α	359	
13. 56000	80. 2	QP	18. 9	7. 0	32. 2	73.9	123.9	50.0	0	Α	359	
13. 56000	77. 9	QP	18. 9	7. 0	32. 2	71.6	123.9	52. 3	90	С	256	
13. 56000	77. 0	QP	18. 9	7. 0	32. 2	70.7	123.9	53. 2	45	В	1	
13. 56000	78. 1	QP	18. 9	7. 0	32. 2	71.8	123.9	52. 1	135	C	223	
13. 56000	70. 2	QP	18. 9	7. 0	32. 2	63.9	123.9	60.0	135	С	123	Hor i
13. 56700		QP	18. 9	7. 0	32. 2	58. 5	90.4	31.9	0	Α	359	
13. 64320	49.7	QP	18. 9	7. 0	32. 2	43.4	90.4	47. 0	0	Α	359	
13. 71000	40.9	QP	18. 9	7. 0	32. 2	34.6	80.5	45. 9	0	Α	359	
13. 77852	47. 6	QP	18. 9	7. 0	32. 2	41.3	80.5	39. 2	0	Α	359	
14. 01000	29. 2	QP	18. 8	7. 0	32. 2	22.8	69.5	46. 7	0	Α	359	
				1						l		
				1								

# UL Japan, Inc. **Head Office EMC Lab.**

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 : YS34D454C2D5002

14.56M Frequency[Hz]

# **Fundamental emission and Spectrum Mask**

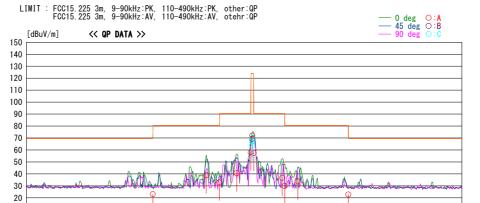
# DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.2 Semi Anechoic Chamber Date: 2012/03/01

Report No. : 32DE0300-H0-02

Temp. / Humi. : 21deg. C / 32% RH
Engineer : Hiroshi Kukita

 $\mbox{Mode}$  /  $\mbox{Remarks}$  : Transmitting (Tx and Rx) without Card mode



Freq.	Reading	DET	Ant. Fac	Loss	Gain	Result	Limit	Margin	Antenna		Table	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	[deg]		[deg]	
13. 11000	29. 2	QP	19. 1	6. 9	32. 2	23.0	69.5	46. 5	0	Α	14	
13. 34963	45. 1	QP	19. 0	6. 9	32. 2	38.8	80.5	41. 7	0	Α	14	
13. 41000		QP	19. 0	6. 9	32. 2	32.9	80.5	47. 6	0	Α	14	
13. 48812		QP	19. 0	7. 0	32. 2	40.4	90.4	50. 0	0	Α	14	
13. 55300		QP	18. 9	7. 0	32. 2	57. 9	90.4	32. 5	0	Α	14	
13. 56000		QP	18. 9	7. 0	32. 2	72.0		51.9	0	Α	14	
13. 56000		QP	18. 9	7. 0	32. 2	69.3		54. 6	45	В	350	
13. 56000	73. 6	QP	18. 9	7. 0	32. 2	67.3	123. 9	56. 6	90	C	14	
13. 56000		QP	18. 9	7. 0	32. 2	69.8		54. 1	135	C	211	
13. 56000		QP	18. 9	7. 0	32. 2	63.8	123. 9	60. 1	135	С	222	Hori
13. 56700		QP	18. 9	7. 0	32. 2	57. 5	90.4	32. 9	0	Α	14	
13.69836		QP	18. 9	7. 0	32. 2	36.7	90.4	53. 7	0	Α	14	
13. 71000	36. 1	QP	18. 9	7. 0	32. 2	29.8	80. 5	50. 7	0	Α	14	
13. 77129	40.0	QP	18. 9	7. 0	32. 2	33.7	80. 5	46. 8	0	Α	14	
14. 01000	29. 2	QP	18. 8	7. 0	32. 2	22.8	69.5	46. 7	0	Α	14	
			l l							ı		

UL Japan, Inc.

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10 0 12, 56M

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# **Spurious emission**

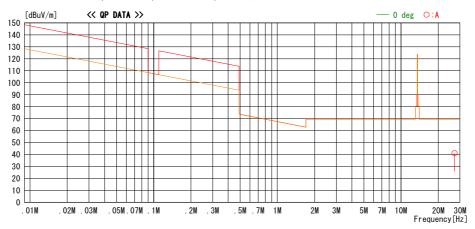
# DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date : 2012/03/01

Report No. : 32DE0300-H0-02 Temp./ Humi. Engineer : 21deg. C / 32% RH : Hiroshi Kukita

 $\label{eq:mode_mode_def} \mbox{Mode} \ / \ \mbox{Remarks} \ \ \mbox{Transmitting (Tx and Rx)} \ \ \mbox{with Card mode (Card distance: 4cm)}$ 

LIMIT : FCC15.225 3m, 9-90kHz:PK, 110-490kHz:PK, other:QP FCC15.225 3m, 9-90kHz:AV, 110-490kHz:AV, other:QP



Freq.	Reading	DET	Ant. Fac	Loss	Gain	Result	Limit	Margin	Antenna		Table	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	[deg]	1	[deg]	
27. 12000		QP	18. 9	7. 5	32. 1			28. 4	0 0	A	359	

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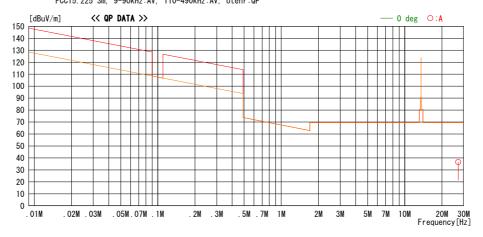
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# **Spurious emission**

# DATA OF RADIATED EMISSION TEST UL Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date: 2012/03/01

Report No. : 32DE0300-H0-02 Temp./ Humi. Engineer : 21deg. C / 32% RH : Hiroshi Kukita

 $\mbox{Mode}$  /  $\mbox{Remarks}$  : Transmitting (Tx and Rx) without Card mode LIMIT : FCC15.225 3m, 9-90kHz:PK, 110-490kHz:PK, other:QP FCC15.225 3m, 9-90kHz:AV, 110-490kHz:AV, other:QP



CHUL 3	Reading	DET	Ant. Fac	Loss	Gain	Result	Limit	Margin	Antenna		Table	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dB]	[dBuV/m]	[dBuV/m]	[dB]	[deg]		[deg]	
27. 12000	42. 3	QP	18. 9	7. 5	32. 1	36. 6	69. 5	32. 9	0	A	328	

UL Japan, Inc. **Head Office EMC Lab.** 

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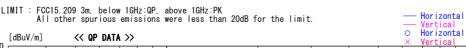
# **Spurious emission**

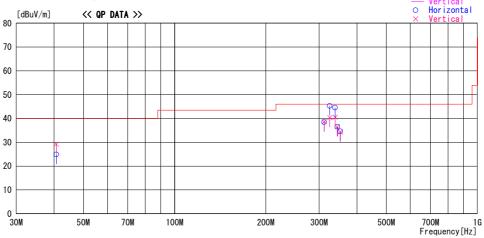
# DATA OF RADIATED EMISSION TEST

Head Office EMC Lab. No.2 Semi Anechoic Chamber Date: 2012/03/01

Report No. : 32DE0300-H0-02 Temp./Humi. Engineer : 22deg. C / 31% RH : Hiroshi Kukita

 $\mbox{Mode}$  /  $\mbox{Remarks}$  : Transmitting (Tx and Rx) with Card mode, Type A





Frequency	Reading	DET	Antenna Factor	Loss& Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]	DLI	[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]	TOTAL.	[dBuV/m]	[dB]	Oommone
40. 680		QP	14. 1	-21. 7		165		Hori.	40. 0	15. 1	
40. 680		QP	14. 1	-21. 7	29. 2	260			40. 0	10.8	
311. 880	42. 5	QP	14. 8	-18. 8		161	100	Hori.	46. 0	7. 5	
311. 880	42. 7	QP	14. 8	-18. 8	38. 7	130	100	Vert.	46. 0	7. 3	
325. 250	48. 9	QP	15. 2	-18. 8	45. 3	328	100	Hori.	46. 0	0.7	
325. 440	44. 0	QP	15. 2	-18. 8	40. 4	215	100	Vert.	46. 0	5. 6	
339. 000	47. 7	QP	15. 6	-18. 8	44. 5	335	100	Hori.	46. 0	1. 5	
339. 001	43. 7	QP	15. 6	-18.8	40. 5	211	100	Vert.	46. 0	5. 5	
344. 677	39. 5	QP	15. 8	-18.8	36. 5	148	100	Hori.	46. 0	9. 5	
344. 678	39. 5	QP	15.8	-18.8	36. 5	134	100	Vert.	46. 0	9. 5	
352. 559	37. 4	QP	16.0	-18. 8	34. 6	150	100	Hori.	46. 0	11. 4	
352. 560	37. 1	QP	16.0	-18.8	34. 3	111	100	Vert.	46. 0	11. 7	

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# **Spurious emission**

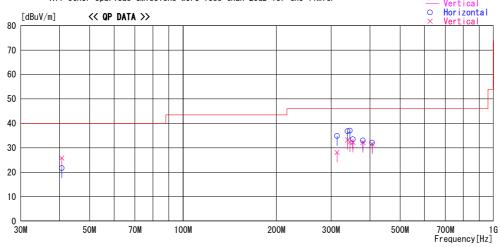
# DATA OF RADIATED EMISSION TEST UL Japan, Inc. Head Office EMC Lab. No. 2 Semi Anechoic Chamber Date: 2012/03/01

: 32DE0300-H0-02 Report No. Temp./Humi. Engineer : 22deg. C / 31% RH : Hiroshi Kukita

 $\mbox{Mode}$  /  $\mbox{Remarks}$  : Transmitting (Tx and Rx) without Card mode, Type A

LIMIT : FCC15.209 3m, below 1GHz:QP, above 1GHz:PK
All other spurious emissions were less than 20dB for the limit.

— Horizontal Horizontal



_			Antenna	Loss&							
Frequency	Reading	DET	Factor	Gain	Level	Angle	Height	Polar.	Limit	Margin	Comment
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
40. 681	29. 3	QP	14. 1	-21. 7	21. 7	171	328	Hori.	40.0	18. 3	
40. 679	33. 4	QP	14. 1	-21.7	25. 8	94	100	Vert.	40.0	14. 2	
313. 344	38.8	QP	14. 8	-18.8	34. 8	351	100	Hori.	46. 0	11. 2	
313. 344	32. 1	QP	14. 8	-18.8	28. 1	164	316	Vert.	46. 0	17. 9	
339. 000	40.0	QP	15. 6	-18.8	36.8	329	100	Hori.	46. 0	9. 2	
338. 999	36. 4	QP	15. 6	-18.8	33. 2	214	100	Vert.	46. 0	12. 8	
344. 678	40.0	QP	15. 8	-18.8	37. 0	146	100	Hori.	46. 0	9. 0	
344. 677	35. 3	QP	15. 8	-18.8	32. 3	225	100	Vert.	46. 0	13. 7	
352. 561	36. 3	QP	16.0	-18.8	33. 5	151	100	Hori.	46. 0	12. 5	
352. 558	35. 0	QP	16.0	-18.8	32. 2	275	179	Vert.	46. 0	13. 8	
379. 681	35.0	QP	16.8	-18.8	33. 0	144	100	Hori.	46. 0	13. 0	
379. 680	34. 1	QP	16.8	-18.8	32. 1	193	100	Vert.	46. 0	13. 9	
406. 799	33. 6	QP	17. 4	-18. 9	32. 1	155	100	Hori.	46. 0	13. 9	
406. 801	33. 0	QP	17. 4	-18. 9	31. 5	199	120	Vert.	46. 0	14. 5	
			l l						l		
			l 1						i		
			l 1						i		
			1						l		
									l		

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

# UL Japan, Inc.

**Head Office EMC Lab.** 

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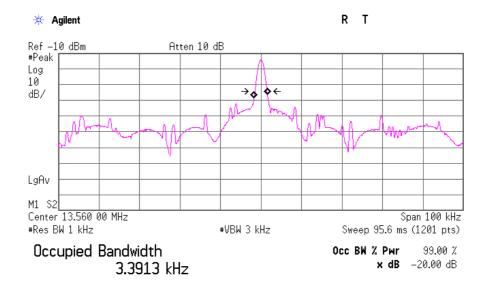
# **20dB Bandwidth**

Test place Head Office EMC Lab. No.2 Semi Anechoic Chamber

Report No. 32DE0300-HO-02 Date 03/02/2012

Temperature/ Humidity 22 deg.C / 31% RH Engineer Hiroshi Kukita Mode Tx Mod on with Card

FREQ	20dB Bandwidth	99% Occupied Bandwidth
[MHz]	[kHz]	[kHz]
13.56	3.01	3.39



Transmit Freq Error -71.041 Hz x dB Bandwidth 3.010 kHz

**Head Office EMC Lab.** 

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# **Frequency Tolerance**

Test place Head Office EMC Lab. No.6 measurement room

Report No. 32DE0300-HO-02
Date 03/02/2012
Temperature/ Humidity 22 deg.C/ 31% RH
Engineer Hiroshi Kukita
Mode Tx Mod on with Card

Test		Test	Measured	Freq	Result	Limit	Margin
Condition		Timing	freq	error		(+/- 0.01%)	
deg.C	Volts		[MHz]	[MHz]	[ppm]	[+/- ppm]	[ppm]
20deg.C		Power on	13.56002156	0.00002156	1.59	100.00	98.41
	20.437	on 2min.	13.56002042	0.00002042	1.51	100.00	98.49
	20.4V	on 5min.	13.56002003	0.00002003	1.48	100.00	98.52
		on 10min.	13.56001904	0.00001904	1.40	100.00	98.60
	24V	Power on	13.56001276	0.00001276	0.94	100.00	99.06
		on 2min.	13.56002714	0.00002714	2.00	100.00	98.00
		on 5min.	13.56002647	0.00002646	1.95	100.00	98.05
		on 10min.	13.56002581	0.00002581	1.90	100.00	98.10
	27.6V	Power on	13.56002752	0.00002752	2.03	100.00	97.97
		on 2min.	13.56002662	0.00002662	1.96	100.00	98.04
		on 5min.	13.56002578	0.00002578	1.90	100.00	98.10
		on 10min.	13.56002515	0.00002515	1.85	100.00	98.15
		Power on	13.55998127	-0.00001873	-1.38	100.00	98.62
40deg.C.		on 2min.	13.55998121	-0.00001879	-1.39	100.00	98.61
	- 24V	on 5min.	13.55998124	-0.00001876	-1.38	100.00	98.62
		on 10min.	13.55998115	-0.00001885	-1.39	100.00	98.61
30deg.C.		Power on	13.55998467	-0.00001533	-1.13	100.00	98.87
		on 2min.	13.55998480	-0.00001520	-1.12	100.00	98.88
		on 5min.	13.55998494	-0.00001506	-1.11	100.00	98.89
		on 10min.	13.55998395	-0.00001605	-1.18	100.00	98.82
		Power on	13.56001276	0.00001276	0.94	100.00	99.06
20deg.C.		on 2min.	13.56002714	0.00002714	2.00	100.00	98.00
		on 5min.	13.56002647	0.00002646	1.95	100.00	98.05
		on 10min.	13.56002581	0.00002581	1.90	100.00	98.10
10deg.C.		Power on	13.56003880	0.00003880	2.86	100.00	97.14
		on 2min.	13.56003878	0.00003878	2.86	100.00	97.14
		on 5min.	13.56003894	0.00003894	2.87	100.00	97.13
		on 10min.	13.56003826	0.00003826	2.82	100.00	97.18
0deg.C.		Power on	13.56005828	0.00005828	4.30	100.00	95.70
		on 2min.	13.56005838	0.00005838	4.30	100.00	95.70
		on 5min.	13.56005827	0.00005827	4.30	100.00	95.70
		on 10min.	13.56005791	0.00005791	4.27	100.00	95.73
-10deg.C.		Power on	13.56006761	0.00006760	4.99	100.00	95.01
		on 2min.	13.56006765	0.00006765	4.99	100.00	95.01
		on 5min.	13.56006764	0.00006764	4.99	100.00	95.01
		on 10min.	13.56006771	0.00006770	4.99	100.00	95.01
Limit ·	13 56	10.55		(±/- 100nnm) =		±/- 0.001356	

Limit: 13.56 13.56 MHz +/-0.01 % (+/- 100ppm) = +/- 0.001356 MHz

# UL Japan, Inc. Head Office EMC Lab.

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<sup>\*</sup> The tests at 50deg.C. and -20deg.C. were not applied since the specification of operating temperature of EUT was -10deg.C. to 40deg.C.

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Revised date : March 16, 2012

FCC ID : YS34D454C2D5002

# **APPENDIX 2: Test instruments**

**EMI** test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-02	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-06902	CE/RE	2011/06/21 * 12
MOS-22	Thermo-Hygrometer	Custom	CTH-201	0003	CE/RE	2012/02/06 * 12
MJM-14	Measure	KOMELON	KMC-36	-	CE/RE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	CE/RE	-
MTR-08	Test Receiver	Rohde & Schwarz	ESCI	100767	CE/RE	2011/08/11 * 12
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	8127363	CE(EUT)	2012/02/06 * 12
MCC-13	Coaxial Cable	Fujikura	3D-2W(12m)/5D- 2W(5m)/5D- 2W(0.8m)/5D- 2W(1m)	-	CE	2012/02/16 * 12
MAT-65	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2012/01/28 * 12
MLPA-01	Loop Antenna	Rohde & Schwarz	HFH2-Z2	100017	RE	2011/10/19 * 12
MCC-31	Coaxial cable	UL Japan	-	-	RE	2011/07/28 * 12
MPA-14	Pre Amplifier	SONOMA INSTRUMENT	310	260833	RE	2011/03/04 * 12
MAT-07	Attenuator(6dB)	Weinschel Corp	2	BK7970	RE	2011/11/02 * 12
MBA-02	Biconical Antenna	Schwarzbeck	BBA9106	VHA91032008	RE	2011/10/23 * 12
MLA-02	Logperiodic Antenna	Schwarzbeck	USLP9143	201	RE	2011/10/23 * 12
MCC-12	Coaxial Cable	Fujikura/Agilent	-	-	RE	2012/02/16 * 12
MPA-09	Pre Amplifier	Agilent	8447D	2944A10845	RE	2011/09/26 * 12
MOS-14	Thermo-Hygrometer	Custom	CTH-201	-	FT	2012/02/06 * 12
MBM-10	Barometer	Sunoh	SBR121	832	FT	2010/12/13 * 36
MSA-10	Spectrum Analyzer	Agilent	E4448A	MY46180655	FT	2012/02/03 * 12
MCC-64	Coaxial Cable	UL Japan	-	-	FT	2011/03/10 * 12
MCH-04	Temperature and Humidity Chamber	Tabai Espec	PL-2KP	14015723	FT	2011/08/22 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: CE: Conducted Emission

**RE: Radiated Emission FT: Frequency Tolerance** 

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